



FIG. 1

10

9

11

12

6

5

4

2

1

3

FIG. 2

FIG. 2 is a schematic diagram of a system for measuring the thickness of a material. The system includes a light source (1) which emits a beam of light (2) through a lens (3) onto a sample (4). The light is reflected by the sample and passes through a series of filters (5, 6, 12) and a detector (9). The detector is connected to a computer (11) which processes the data. The computer also controls the light source (1) and the detector (9). The system is used to measure the thickness of a material by comparing the intensity of the reflected light to a known standard.